



Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from,Europe,America and south Asia,supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of “Quality Parts,Customers Priority,Honest Operation,and Considerate Service”,our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip,ALPS,ROHM,Xilinx,Pulse,ON,Everlight and Freescale. Main products comprise IC,Modules,Potentiometer,IC Socket,Relay,Connector.Our parts cover such applications as commercial,industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China





LSM320DL

Linear sensor module 3D accelerometer sensor and 2D gyroscope sensor

Preliminary data

Features

- Analog supply voltage 2.4 V to 3.6 V
- Digital supply voltage IOs, 1.8 V
- Low power mode
- Power-down mode
- 3 independent acceleration channels and 2 angular rate channels (pitch and yaw)
- $\pm 2g/\pm 4g/\pm 8/\pm 16g$ dynamically selectable full-scale
- $\pm 250/\pm 500/\pm 2000$ dps dynamically selectable full-scale
- Embedded temperature sensor
- SPI/I²C serial interface (16-bit data output)
- Programmable interrupt generator for free-fall and motion detection
- ECOPACK[®] RoHS and “Green” compliant

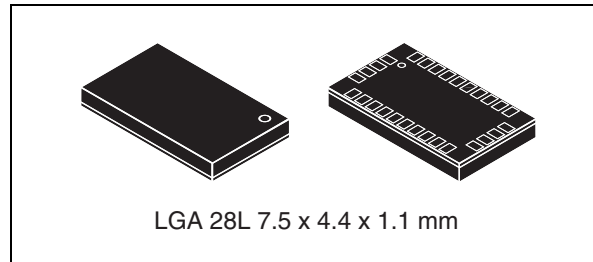
Applications

- GPS navigation systems
- Impact recognition and logging
- Gaming and virtual reality input devices
- Motion activated functions
- Intelligent power saving for handheld devices
- Vibration monitoring and compensation
- Free-fall detection
- 6D orientation detection

Description

The LSM320DL is a system-in-package featuring a 3D digital accelerometer and a 2D digital gyroscope.

The ST modules family uses a robust and mature manufacturing process already used for the production of micromachined accelerometers.



The various sensing elements are manufactured using specialized micromachining processes, while the IC interfaces are realized using a CMOS technology that allows to design a dedicated circuit which is trimmed to better match the sensing element characteristics.

LSM320DL has a dynamic user selectable full-scale acceleration range of $\pm 2g/\pm 4g/\pm 8/\pm 16g$ and angular rate of $\pm 250/\pm 500/\pm 2000$ deg/sec.

The accelerometer and gyroscope sensors can be either activated or put in low power/power-down mode separately for application optimized power saving.

The LSM320DL is available in a plastic land grid array (LGA) package.

Several years ago ST successfully pioneered the use of this package for accelerometers. Today, ST has the widest manufacturing capability and strongest expertise in the world for production of sensors in a plastic LGA package.

Table 1. Device summary

Order codes	Temperature range [°C]	Package	Packing
LSM320DL	-40 to +85	LGA 28L	Tray
LSM320DLTR			Tape and reel

Contents

- 1 Block diagram and pin description 9**
 - 1.1 Block diagram 9
 - 1.2 Pin description 10

- 2 Module specifications 12**
 - 2.1 Mechanical characteristics 12
 - 2.2 Electrical characteristics 13
 - 2.3 Temperature sensor characteristics 14
 - 2.4 Communication interface characteristics 15
 - 2.4.1 SPI - serial peripheral interface 15
 - 2.4.2 I2C - inter IC control interface 16
 - 2.5 Absolute maximum ratings 17
 - 2.6 Terminology 18
 - 2.6.1 Sensitivity 18
 - 2.6.2 Zero level 18

- 3 Functionality 19**
 - 3.1 Factory calibration 19

- 4 Application hints 20**
 - 4.1 External capacitors 20
 - 4.2 Soldering information 21

- 5 Digital interfaces 22**
 - 5.1 I2C serial interface 22
 - 5.1.1 I2C operation 23
 - 5.2 SPI bus interface 25
 - 5.2.1 SPI read 26
 - 5.2.2 SPI write 26
 - 5.2.3 SPI read in 3-wire mode 27

- 6 Register mapping 28**

7	Registers description	30
7.1	CTRL_REG1_A (20h)	30
7.2	CTRL_REG2_A (21h)	31
7.3	CTRL_REG3_A (22h)	31
7.4	CTRL_REG4_A (23h)	32
7.5	CTRL_REG5_A (24h)	32
7.6	CTRL_REG6_A (25h)	33
7.7	REFERENCE/DATACAPTURE_A (26h)	33
7.8	STATUS_REG_A (27h)	33
7.9	OUT_X_L_A (28h), OUT_X_H_A (29h)	34
7.10	OUT_Y_L_A (2Ah), OUT_Y_H_A (2Bh)	34
7.11	OUT_Z_L_A(2Ch), OUT_Z_H_A (2Dh)	34
7.12	FIFO_CTRL_REG_A (2Eh)	34
7.13	FIFO_SRC_REG_A (2Fh)	35
7.14	INT1_CFG_A (30h)	35
7.15	INT1_SRC_A (31h)	36
7.16	INT1_THS_A (32h)	36
7.17	INT1_DURATION_A (33h)	37
7.18	CLICK_CFG_A (38h)	37
7.19	CLICK_SRC_A (39h)	37
7.20	CLICK_THS_A (3Ah)	38
7.21	TIME_LIMIT_A (3Bh)	38
7.22	TIME_LATENCY_A (3Ch)	38
7.23	TIME WINDOW_A (3Dh)	39
7.24	CTRL_REG1_G (20h)	39
7.25	CTRL_REG2_G (21h)	40
7.26	CTRL_REG3_G (22h)	41
7.27	CTRL_REG4_G (23h)	42
7.28	CTRL_REG5_G (24h)	42
7.29	REFERENCE/DATACAPTURE_G (25h)	44
7.30	OUT_TEMP_G (26h)	44
7.31	STATUS_REG_G (27h)	44
7.32	OUT_X_L_G (28h), OUT_X_H_G (29h)	45

7.33	OUT_Z_L_G (2Ch), OUT_Z_H_G (2Dh)	45
7.34	FIFO_CTRL_REG_G (2Eh)	45
7.35	FIFO_SRC_REG_G (2Fh)	45
7.36	INT1_CFG_G (30h)	46
7.37	INT1_SRC_G (31h)	46
7.38	INT1_THS_XH_G (32h)	47
7.39	INT1_THS_XL_G (33h)	47
7.40	INT1_THS_ZH_G (36h)	47
7.41	INT1_THS_ZL_G (37h)	48
7.42	INT1_DURATION_G (38h)	48
8	Package information	50
9	Revision history	52

List of tables

Table 1.	Device summary	1
Table 2.	Pin description	10
Table 3.	Mechanical characteristics	12
Table 4.	Electrical characteristics	13
Table 5.	Temperature sensor characteristics	14
Table 6.	SPI slave timing values	15
Table 7.	I2C slave timing values	16
Table 8.	Absolute maximum ratings	17
Table 9.	Part list	20
Table 10.	Serial interface pin description	22
Table 11.	Serial interface pin description	22
Table 12.	Transfer when master is writing one byte to slave	23
Table 13.	Transfer when master is writing multiple bytes to slave:	23
Table 14.	Transfer when master is receiving (reading) one byte of data from slave:	23
Table 15.	Transfer when master is receiving (reading) multiple bytes of data from slave	23
Table 16.	Linear acceleration SAD+Read/Write patterns	24
Table 17.	Angular rate SAD+Read/Write patterns	24
Table 18.	Register address map	28
Table 19.	CTRL_REG1_A register	30
Table 20.	CTRL_REG1_A description	30
Table 21.	Data rate configuration	30
Table 22.	CTRL_REG2_A register	31
Table 23.	CTRL_REG2_A description	31
Table 24.	High pass filter mode configuration	31
Table 25.	CTRL_REG3_A register	31
Table 26.	CTRL_REG3_A description	31
Table 27.	CTRL_REG4_A register	32
Table 28.	CTRL_REG4_A description	32
Table 29.	CTRL_REG5_A register	32
Table 30.	CTRL_REG5_A description	32
Table 31.	CTRL_REG6_A register	33
Table 32.	CTRL_REG6 description	33
Table 33.	REFERENCE_A register	33
Table 34.	REFERENCE register description	33
Table 35.	STATUS_REG_A register	33
Table 36.	STATUS_REG_A register description	33
Table 37.	FIFO_CTRL_REG_A register	34
Table 38.	FIFO_CTRL_REG_A register description	34
Table 39.	FIFO mode configuration	34
Table 40.	FIFO_SRC_REG_A register	35
Table 41.	INT1_CFG_REG_A register	35
Table 42.	INT1_CFG_REG_A description	35
Table 43.	Interrupt mode	35
Table 44.	INT1_SRC_A register	36
Table 45.	INT1_SRC_A description	36
Table 46.	INT1_THS_A register	36
Table 47.	INT1_THS_A description	36
Table 48.	INT1_DURATION_Aregister	37

Table 49.	INT1_DURATION_A description	37
Table 50.	CLICK_CFG_A register	37
Table 51.	CLICK_CFG_A description	37
Table 52.	CLICK_SRC_A register	37
Table 53.	CLICK_SRC_A description	38
Table 54.	CLICK_THS_A register	38
Table 55.	CLICK_SRC_A description	38
Table 56.	TIME_LIMIT_A register	38
Table 57.	TIME_LIMIT_A description	38
Table 58.	TIME_LATENCY_A register	38
Table 59.	TIME_LATENCY_A description	39
Table 60.	TIME_WINDOW_A register	39
Table 61.	TIME_WINDOW_A description	39
Table 62.	CTRL_REG1_G register	39
Table 63.	CTRL_REG1_G description	39
Table 64.	DR and BW configuration setting	40
Table 65.	Power mode selection configuration	40
Table 66.	CTRL_REG2_G register	40
Table 67.	CTRL_REG2_G description	41
Table 68.	High pass filter mode configuration	41
Table 69.	High pass filter cut-off frequency configuration [Hz]	41
Table 70.	CTRL_REG1_G register	41
Table 71.	CTRL_REG3_G description	41
Table 72.	CTRL_REG4_G register	42
Table 73.	CTRL_REG4_G description	42
Table 74.	CTRL_REG5_G register	42
Table 75.	CTRL_REG5_G description	42
Table 76.	Out_Sel configuration setting	43
Table 77.	INT_SEL configuration setting	43
Table 78.	REFERENCE_G register	44
Table 79.	REFERENCE_G register description	44
Table 80.	OUT_TEMP_G register	44
Table 81.	OUT_TEMP_G register description	44
Table 82.	STATUS_REG_G register	44
Table 83.	STATUS_REG_G description	44
Table 84.	REFERENCE_G register	45
Table 85.	REFERENCE_G register description	45
Table 86.	FIFO mode configuration	45
Table 87.	FIFO_SRC_G register	45
Table 88.	FIFO_SRC_G register description	46
Table 89.	INT1_CFG_G register	46
Table 90.	INT1_CFG_G description	46
Table 91.	INT1_SRC_G register	46
Table 92.	INT1_SRC_G description	47
Table 93.	INT1_THS_XH_G register	47
Table 94.	INT1_THS_XH_G description	47
Table 95.	INT1_THS_XL_G register	47
Table 96.	INT1_THS_XL_G description	47
Table 97.	INT1_THS_ZH_G register	47
Table 98.	INT1_THS_ZH_G description	48
Table 99.	INT1_THS_ZL_G register	48

Table 100.	INT1_THS_ZL_G description	48
Table 101.	INT1_DURATION_G register	48
Table 102.	INT1_DURATION_G description	48
Table 103.	LGA 28L 7.5 x 4.4 x 1.1 mechanical data	51
Table 104.	Document revision history	52

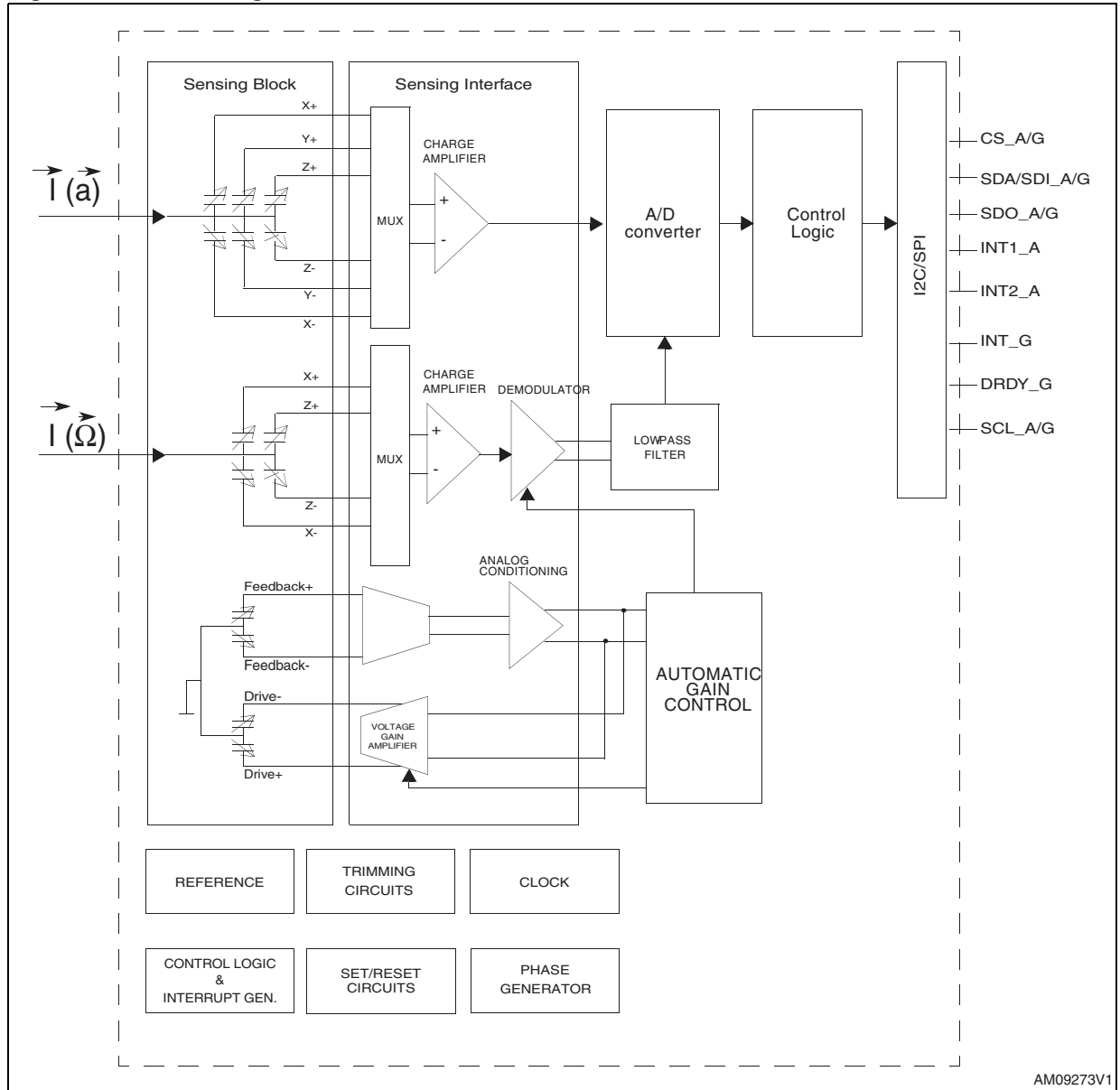
List of figures

Figure 1. Block diagram 9
Figure 2. Pin connection 10
Figure 3. SPI slave timing diagram 15
Figure 4. I2C slave timing diagram 16
Figure 5. LSM320DL electrical connection 20
Figure 6. Read and write protocol 25
Figure 7. SPI read protocol 26
Figure 8. Multiple bytes SPI read protocol (2 bytes example) 26
Figure 9. SPI write protocol 26
Figure 10. Multiple bytes SPI write protocol (2 bytes example) 27
Figure 11. SPI read protocol in 3-wire mode 27
Figure 12. INT1_Sel and Out_Sel configuration block diagram 43
Figure 13. Wait disabled 49
Figure 14. Wait enabled 49
Figure 15. LGA 28L 7.5 x 4.4 x 1.1 package drawing 51

1 Block diagram and pin description

1.1 Block diagram

Figure 1. Block diagram



1.2 Pin description

Figure 2. Pin connection

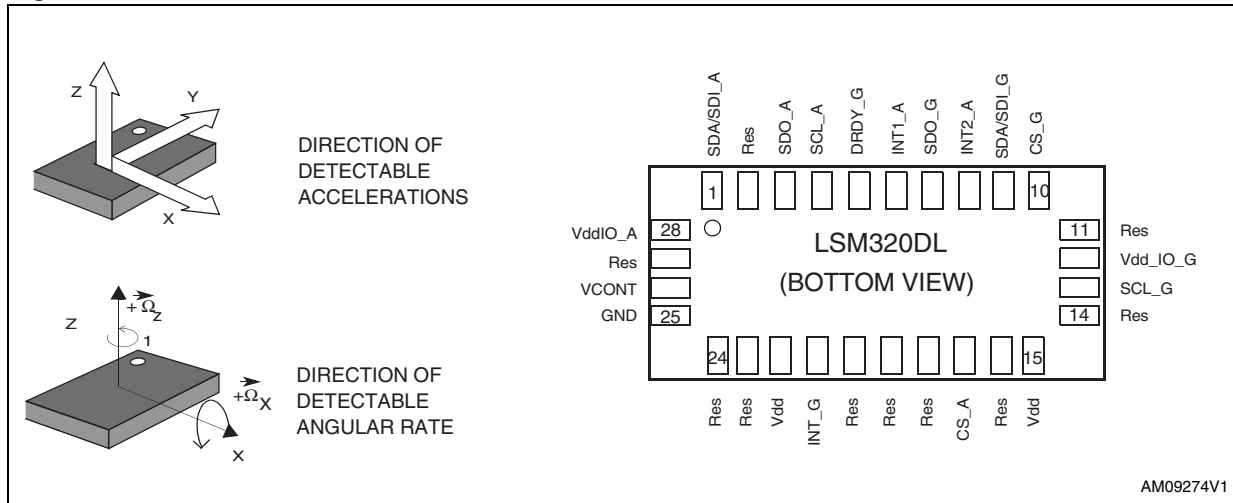


Table 2. Pin description

Pin#	Name	Function
1	SDA/SDI_A	Accelerometer: I ² C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO)
2	Res	Reserved connect to GND
3	SDO_A	Accelerometer: SPI serial data output (SDO) I ² C least significant bit of the device address (SA0)
4	SCL_A	Accelerometer: I ² C serial clock (SCL) SPI serial port clock (SPC)
5	DRDY_G	Gyroscope data ready
6	INT1_A	Accelerometer interrupt signal
7	SDO_G	Gyroscope: SPI serial data output (SDO) I ² C least significant bit of the device address (SA0)
8	INT2_A	Accelerometer interrupt signal
9	SDA/SDI_G	Gyroscope: I ² C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO)

Table 2. Pin description (continued)

Pin#	Name	Function
10	CS_G	Gyroscope: SPI enable I ² C/SPI mode selection (1: SPI idle mode / I ² C communication enabled; 0: SPI communication mode / I ² C disabled)
11	Res	Reserved connect to GND
12	VddIO_G	Gyroscope power supply for IO pins
13	SCL_G	Gyroscope: I ² C serial clock (SCL) SPI serial port clock (SPC)
14	Res	Reserved connect to GND
15	Vdd	Power supply
16	Res	Reserved connect to GND
17	CS_A	Accelerometer: SPI enable I ² C/SPI mode selection (1: SPI idle mode / I ² C communication enabled; 0: SPI communication mode / I ² C disabled)
18	Res	Reserved connect to GND
19	Res	Reserved connect to GND
20	Res	Reserved connect to GND
21	INT_G	Gyroscope interrupt signal
22	Vdd	Power supply
23	Res	Reserved connect to GND
24	Res	Reserved connect to GND
25	GND	0 V power supply
26	VCONT	PLL filter connection
27	Res	Reserved connect to GND
28	VddIO_A	Accelerometer power supply for IO pins

2 Module specifications

2.1 Mechanical characteristics

@ Vdd = 3V, T = 25 °C unless otherwise noted^(a).

Table 3. Mechanical characteristics

Symbol	Parameter	Test conditions	Min.	Typ. ⁽¹⁾	Max.	Unit
LA_FS	Linear acceleration measurement range ⁽²⁾	FS bit set to 00		±2.0		g
		FS bit set to 01		±4.0		
		FS bit set to 10		±8.0		
		FS bit set to 11		±16.0		
G_FS	Angular rate measurement range ⁽²⁾	FS bit set to 00		±250		dps
		FS bit set to 01		±500		
		FS bit set to 10		±2000		
LA_So	Linear acceleration sensitivity	FS bit set to 00		1		mg/digit
		FS bit set to 01		2		
		FS bit set to 10		4		
		FS bit set to 11		12		
G_So	Angular rate sensitivity	FS bit set to 00		8.75		mdps/digit
		FS bit set to 01		17.5		
		FS bit set to 10		70		
LA_So	Linear acceleration sensitivity change vs. temperature	FS bit set to 00		±0.05		%/°C
G_So	Angular rate sensitivity change vs. temperature	From -40 to +85 °C		±2		%
LA_TyOff	Typical Zero-g level offset accuracy ⁽³⁾	FS bit set to 00		±60		mg
G_TyOff	Typical zero-rate level ⁽⁴⁾	FS bit set to 00		10		LSb
LA_TCOff	Zero-g level change vs. temperature	Max. delta from 25 °C		±0.5		mg/°C
G_TCOff	Zero-rate level change vs. temperature	FS bit set to 00 from -40 to +85 °C		±0.03		dps/°C
An	Acceleration noise density	FS bit set to 00 Normal mode, ODR bit set to 1001		220		μg/√Hz
Rn	Rate noise density	FS bit set to 00		0.03		°/s/√Hz
Top	Operating temperature range		-40		+85	°C

a. The product is factory calibrated at 3 V. The operational power supply range is from 2.4 V to 3.6 V.

1. Typical specifications are not guaranteed.
2. Verified by wafer level test and measurement of initial offset and sensitivity.
3. Typical Zero-g level offset value after MSL3 preconditioning.
4. Offset can be eliminated by enabling the built-in high pass filter.

2.2 Electrical characteristics

@ Vdd = 3 V, T = 25 °C unless otherwise noted.

Table 4. Electrical characteristics

Symbol	Parameter	Test conditions	Min.	Typ. ⁽¹⁾	Max.	Unit
Vdd	Supply voltage		2.4		3.6	V
Vdd_IO	Power supply for I/O		1.71		Vdd+0.1	V
LA_Idd	LA current consumption in normal mode	ODR = 50Hz		11		μA
		ODR = 1Hz		2		
LA_IddLowP	LA current consumption in low power mode	ODR = 50Hz		6		μA
LA_IddPdn	LA current consumption in power-down mode	T = 25°C		0.5		μA
G_Idd	AR current consumption in normal mode			6		mA
G_IddSL	Supply current in sleep mode ⁽²⁾			1.5		mA
G_IddPdn	AR current consumption in power-down mode	T = 25 °C		5		μA
VIH	Digital high level input voltage		0.8*Vdd_IO			V
VIL	Digital low level input voltage				0.2*Vdd_IO	V
VOH	High level output voltage		0.9*Vdd_IO			V
VOL	Low level output voltage				0.1*Vdd_IO	V
Top	Operating temperature range		-40		+85	°C

1. Typical specifications are not guaranteed.
2. Sleep mode introduces a faster turn-on time compared to power-down mode.

2.3 Temperature sensor characteristics

@ V_{dd} = 3.0 V, T = 25 °C, unless otherwise noted.^(b)

Table 5. Temperature sensor characteristics

Symbol	Parameter	Test condition	Min.	Typ. ⁽¹⁾	Max.	Unit
TSDr	Temperature sensor output change vs. temperature	-		-1		°C/digit
TODR	Temperature refresh rate			1		Hz
Top	Operating temperature range		-40		+85	°C

1. Typical specifications are not guaranteed.

b. The product is factory calibrated at 3.0 V.

2.4 Communication interface characteristics

2.4.1 SPI - serial peripheral interface

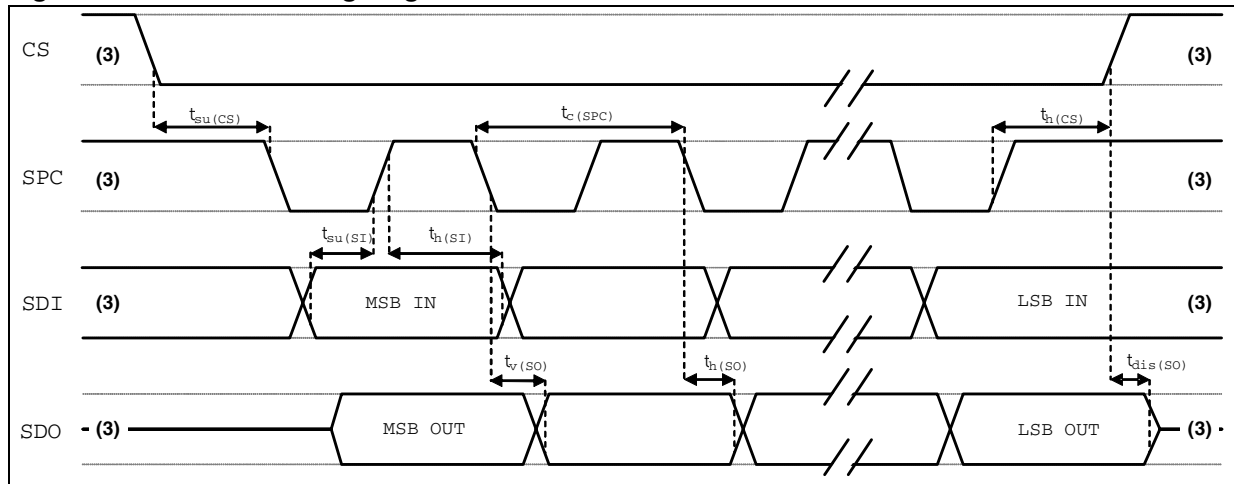
Subject to general operating conditions for Vdd and Top.

Table 6. SPI slave timing values

Symbol	Parameter	Value ⁽¹⁾		Unit
		Min.	Max.	
tc(SPC)	SPI clock cycle	100		ns
fc(SPC)	SPI clock frequency		10	MHz
tsu(CS)	CS setup time	6		ns
th(CS)	CS hold time	8		
tsu(SI)	SDI input setup time	5		
th(SI)	SDI input hold time	15		
tv(SO)	SDO valid output time		50	
th(SO)	SDO output hold time	9		
tdis(SO)	SDO output disable time		50	

1. Values are guaranteed at 10 MHz clock frequency for SPI with both 4 and 3 wires, based on characterization results, not tested in production.

Figure 3. SPI slave timing diagram ^(c)



3. When no communication is on-going, data on CS, SPC, SDI, and SDO are driven by internal pull-up resistors.

c. Measurement points are done at 0.2·Vdd_IO and 0.8·Vdd_IO, for both input and output ports.

2.4.2 I²C - inter IC control interface

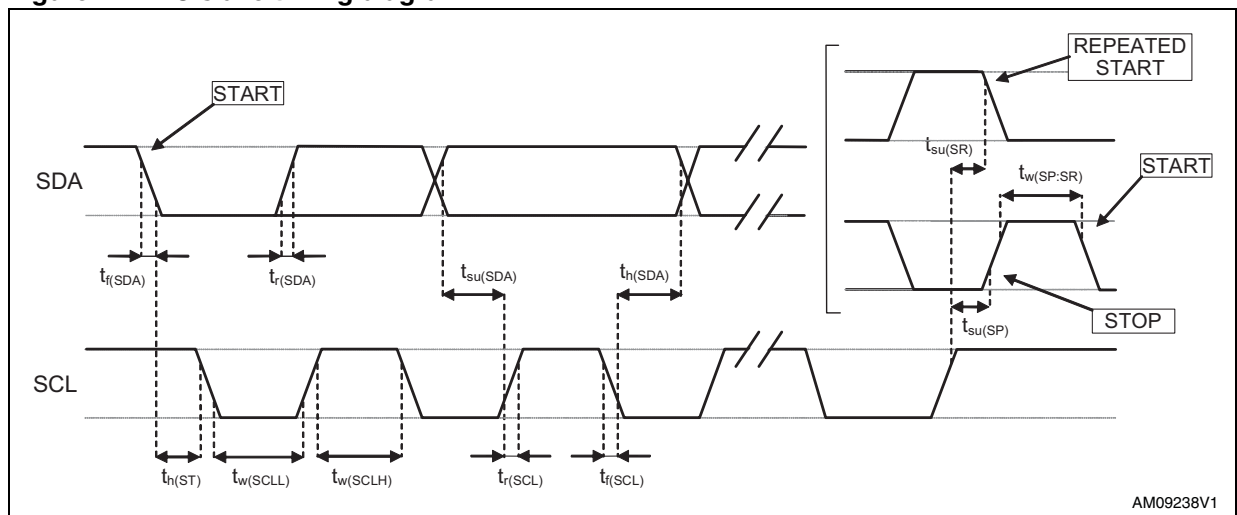
Subject to general operating conditions for Vdd and Top.

Table 7. I²C slave timing values

Symbol	Parameter	I ² C standard mode ⁽¹⁾		I ² C fast mode ⁽¹⁾		Unit
		Min.	Max.	Min.	Max.	
f _(SCL)	SCL clock frequency	0	100	0	400	KHz
t _{w(SCLL)}	SCL clock low time	4.7		1.3		µs
t _{w(SCLH)}	SCL clock high time	4.0		0.6		
t _{su(SDA)}	SDA setup time	250		100		ns
t _{h(SDA)}	SDA data hold time	0,01	3.45	0	0.9	µs
t _{r(SDA)} t _{r(SCL)}	SDA and SCL rise time		1000	20 + 0.1C _b ⁽²⁾	300	ns
t _{f(SDA)} t _{f(SCL)}	SDA and SCL fall time		300	20 + 0.1C _b ⁽²⁾	300	
t _{h(ST)}	START condition hold time	4		0.6		µs
t _{su(SR)}	Repeated START condition setup time	4.7		0.6		
t _{su(SP)}	STOP condition setup time	4		0.6		
t _{w(SP:SR)}	Bus free time between STOP and START condition	4.7		1.3		

1. Data based on standard I²C protocol requirement, not tested in production.
2. C_b = total capacitance of one bus line, in pF.

Figure 4. I²C slave timing diagram (d)



d. Measurement points are done at 0.2·Vdd_IO and 0.8·Vdd_IO, for both ports.

2.5 Absolute maximum ratings

Stresses above those listed as “absolute maximum ratings” may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 8. Absolute maximum ratings

Symbol	Ratings	Maximum value	Unit
V _{dd}	Supply voltage	-0.3 to 4.8	V
V _{dd_IO}	I/O pins supply voltage	-0.3 to 4.8	V
V _{in}	Input voltage on any control pin (SCL, SDA/SDI)	-0.3 to V _{dd_IO} +0.3	V
A _{POW}	Acceleration (any axis, powered, V _{dd} = 3 V)	3000 g for 0.5 ms	
		10000 g for 0.1 ms	
A _{UNP}	Acceleration (any axis, unpowered)	3000 g for 0.5 ms	
		10000 g for 0.1 ms	
T _{OP}	Operating temperature range	-40 to +85	°C
T _{STG}	Storage temperature range	-40 to +125	°C
ESD	Electrostatic discharge protection	2 (HBM)	kV



This is a mechanical shock sensitive device, improper handling can cause permanent damage to the part



This is an ESD sensitive device, improper handling can cause permanent damage to the part

2.6 Terminology

2.6.1 Sensitivity

Linear acceleration sensitivity can be determined, for example, by applying 1 *g* acceleration to the device. As the sensor can measure DC accelerations this can be done easily by pointing the axis of interest towards the center of the Earth, noting the output value, rotating the sensor by 180 degrees (pointing to the sky) and noting the output value again. By doing so, ± 1 *g* acceleration is applied to the sensor. Subtracting the larger output value from the smaller one, and dividing the result by 2, leads to the actual sensitivity of the sensor. This value changes very little over temperature and also very little over time. The sensitivity tolerance describes the range of sensitivities of a large population of sensors.

Angular rate sensitivity describes the angular rate gain of the sensor and can be determined by applying a defined angular velocity to it. This value changes very little over temperature and also very little over time.

2.6.2 Zero level

Linear acceleration Zero-*g* level offset (TyOff) describes the deviation of an actual output signal from the ideal output signal if no acceleration is present. A sensor in a steady-state on a horizontal surface measures 0 *g* in the X axis and 0 *g* in the Y axis, whereas the Z axis measures 1 *g*. The output is ideally in the middle of the dynamic range of the sensor (content of OUT registers 00h, data expressed as 2's complement number). A deviation from the ideal value in this case is called Zero-*g* offset. Offset is, to some extent, a result of stress to the MEMS sensor and therefore the offset can slightly change after mounting the sensor onto a printed circuit board or exposing it to extensive mechanical stress. The offset changes little over temperature, see "Zero-*g* level change vs. temperature". The Zero-*g* level tolerance (TyOff) describes the standard deviation of the range of Zero-*g* levels of a population of sensors.

Angular rate zero-rate level describes the actual output value if there is no angular rate present. The zero-rate level of precise MEMS sensors is, to some extent, a result of stress to the sensor and therefore zero-rate level can slightly change after mounting the sensor onto a printed circuit board or after exposing it to extensive mechanical stress. This value changes very little over temperature and also very little over time.

3 Functionality

The LSM320DL is a system-in-package featuring a 3D digital accelerometer and a 2D digital gyroscope.

The complete device includes specific sensing elements and two IC interfaces able to measure both the acceleration and angular rate applied to the module and to provide a signal to the external world through an SPI/I²C serial interface.

The various sensing elements are manufactured using specialized micromachining processes, while the IC interfaces are realized using a CMOS technology that allows to design a dedicated circuit which is trimmed to better match the sensing element characteristics.

The LSM320DL may also be configured to generate an inertial wake-up and free-fall interrupt signal according to a programmed acceleration event along the enabled axes.

3.1 Factory calibration

The IC interface is factory calibrated for sensitivity and zero level. The trimming values are stored inside the device by a non-volatile memory. Any time the device is turned on, the trimming parameters are downloaded into the registers to be used during the normal operation. This allows the user to use the device without further calibration.

4 Application hints

Figure 5. LSM320DL electrical connection

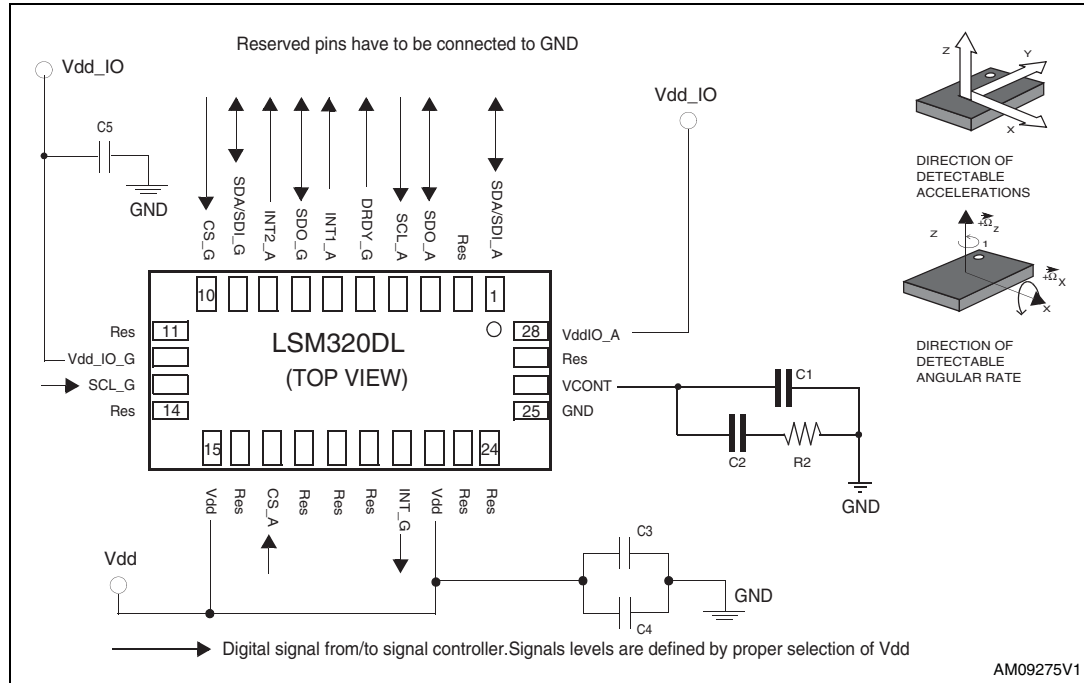


Table 9. Part list

Component	Typical value
C1	10 nF
C2	470 nF
C3	10 μF
C4	100 nF
C5	100 nF
R2	10 kOhm

4.1 External capacitors

The device core is supplied through Vdd line. Power supply decoupling capacitors (C4=100 nF ceramic, C3=10 μF Al) should be placed as near as possible to the supply pin of the device (common design practice).

All the voltage and ground supplies must be present at the same time to have proper behavior of the IC (refer to [Figure 5](#)).

The functionality of the device and the measured acceleration/angular rate data is selectable and accessible through the SPI/I²C interface.

The functions, the threshold, and the timing of the two interrupt pins for each sensor can be completely programmed by the user through the SPI/I²C interface.

4.2 Soldering information

The LGA package is compliant with the ECOPACK[®], RoHS and “Green” standard. It is qualified for soldering heat resistance according to JEDEC J-STD-020D.

Leave “Pin 1 Indicator” unconnected during soldering.

Land pattern and soldering recommendations are available at www.st.com/mems.

5 Digital interfaces

The registers embedded inside the LSM320DL may be accessed through both the I²C and SPI serial interfaces. The latter may be SW configured to operate either in 3-wire or 4-wire interface mode.

To select/exploit the I²C interface, CS line must be tied high (i.e. connected to Vdd_IO).

Table 10. Serial interface pin description

Pin name	Pin description
CS_A	Linear acceleration SPI enable Linear acceleration I ² C/SPI mode selection (1: I ² C mode; 0: SPI enabled)
CS_G	Angular Rate SPI enable Angular Rate I ² C/SPI mode selection (1: I ² C mode; 0: SPI enabled)
SCL_A SCL_G	I ² C serial clock (SCL) SPI serial port clock (SPC)
SDA/SDI_A SDA/SDI_G	I ² C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO)
SDO_A SDO_G	I ² C less significant bit of the device address (SA0) SPI serial data output (SDO)

5.1 I²C serial interface

The LSM320DL I²C is a bus slave. The I²C is employed to write the data into the registers whose content can also be read back.

The relevant I²C terminology is given in the table below.

Table 11. Serial interface pin description

Term	Description
Transmitter	The device which sends data to the bus
Receiver	The device which receives data from the bus
Master	The device which initiates a transfer, generates clock signals and terminates a transfer
Slave	The device addressed by the master

There are two signals associated with the I²C bus: the serial clock line (SCL) and the serial data line (SDA). The latter is a bidirectional line used for sending and receiving the data to/from the interface.

5.1.1 I²C operation

The transaction on the bus is started through a START (ST) signal. A START condition is defined as a HIGH to LOW transition on the data line while the SCL line is held HIGH. After this has been transmitted by the master, the bus is considered busy. The next byte of data transmitted after the start condition contains the address of the slave in the first 7 bits and the eighth bit tells whether the master is receiving data from the slave or transmitting data to the slave. When an address is sent, each device in the system compares the first seven bits after a start condition with its address. If they match, the device considers itself addressed by the master.

Data transfer with acknowledge is mandatory. The transmitter must release the SDA line during the acknowledge pulse. The receiver must then pull the data line LOW so that it remains stable low during the HIGH period of the acknowledge clock pulse. A receiver which has been addressed is obliged to generate an acknowledge after each byte of data received.

The I²C embedded inside the LSM320DL behaves as a slave device and the following protocol must be adhered to. After the start condition (ST), a slave address is sent, once a slave acknowledge (SAK) has been returned, an 8-bit sub-address (SUB) is transmitted: the 7 LSb represent the actual register address while the MSB enables address auto increment. If the MSb of the SUB field is '1', the SUB (register address) is automatically increased to allow multiple data read/write.

Table 12. Transfer when master is writing one byte to slave

Master	ST	SAD + W		SUB		DATA		SP
Slave			SAK		SAK		SAK	

Table 13. Transfer when master is writing multiple bytes to slave:

Master	ST	SAD + W		SUB		DATA		DATA		SP
Slave			SAK		SAK		SAK		SAK	

Table 14. Transfer when master is receiving (reading) one byte of data from slave:

Master	ST	SAD + W		SUB		SR	SAD + R			NMAK	SP
Slave			SAK		SAK			SAK	DATA		

Table 15. Transfer when master is receiving (reading) multiple bytes of data from slave

Master	ST	SAD+W		SUB		SR	SAD+R			MAK		MAK		NMAK	SP
Slave			SAK		SAK			SAK	DATA		DATA		DATA		

Data are transmitted in byte format (DATA). Each data transfer contains 8 bits. The number of bytes transferred per transfer is unlimited. Data is transferred with the most significant bit (MSb) first. If a receiver can't receive another complete byte of data until it has performed some other function, it can hold the clock line, SCL LOW, to force the transmitter into a wait

state. Data transfer only continues when the receiver is ready for another byte and releases the data line. If a slave receiver doesn't acknowledge the slave address (i.e. it is not able to receive because it is performing some real time function), the data line must be left HIGH by the slave. The master can then abort the transfer. A LOW to HIGH transition on the SDA line while the SCL line is HIGH is defined as a STOP condition. Each data transfer must be terminated by the generation of a STOP (SP) condition.

In order to read multiple bytes, it is necessary to assert the most significant bit of the sub-address field. In other words, SUB(7) must be equal to 1 while SUB(6-0) represents the address of the first register to be read.

In the presented communication format, MAK is Master Acknowledge, and NMAK is No Master Acknowledge.

Default address:

The **SDO/SA0** pad can be used to modify less significant bits of the device address. If the SA0 pad is connected to voltage supply, LSb is '1' (ex. address 0011001b), or else, if the SA0 pad is connected to ground, the LSb value is '0' (ex address 0011000b).

The slave address is completed with a Read/Write bit. If the bit is '1' (Read), a repeated START (SR) condition must be issued after the two sub-address bytes; if the bit is '0' (Write) the master transmits to the slave with direction unchanged. [Table 16](#) and [Table 17](#) explain how the SAD+Read/Write bit pattern is composed, listing all the possible configurations.

Linear acceleration address: the default (factory) 7-bit slave address is 001100xb.

Table 16. Linear acceleration SAD+Read/Write patterns

Command	SAD[6:1]	SAD[0] = SA0	R/W	SAD+R/W
Read	001100	0	1	00110001 (31h)
Write	001100	0	0	00110000 (30h)
Read	001100	1	1	00110011 (33h)
Write	001100	1	0	00110010 (32h)

Angular rate sensor: the default (factory) 7-bit slave address is 110100xb.

Table 17. Angular rate SAD+Read/Write patterns

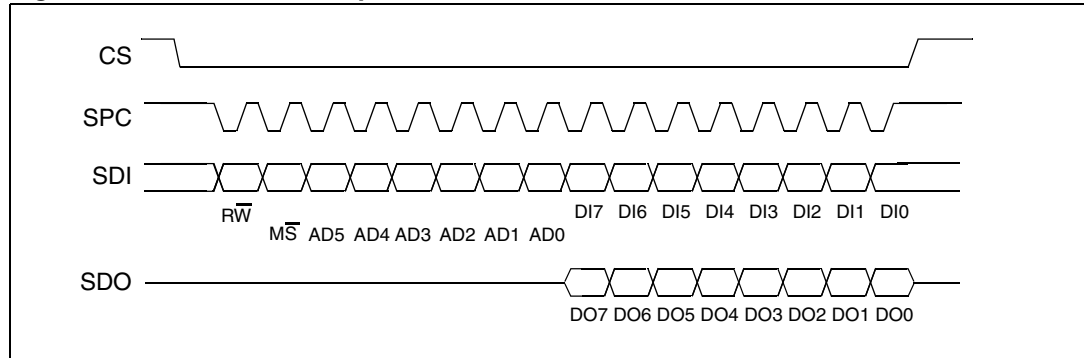
Command	SAD[6:1]	SAD[0] = SA0	R/W	SAD+R/W
Read	110100	0	1	11010001 (F1h)
Write	110100	0	0	11010000 (F0h)
Read	110100	1	1	11010011 (F3h)
Write	110100	1	0	11010010 (F2h)

5.2 SPI bus interface

The LSM320DL SPI is a bus slave. The SPI allows to write and read the registers of the device.

The serial interface interacts with the outside world with 4 wires: **CS**, **SPC**, **SDI**, and **SDO**.(SPC, SDI, SDO are common)

Figure 6. Read and write protocol



CS is the serial port enable and it is controlled by the SPI master. It goes low at the start of the transmission and returns to high at the end. **SPC** is the serial port clock and it is controlled by the SPI master. It is stopped high when **CS** is high (no transmission). **SDI** and **SDO** are respectively the serial port data input and output. Those lines are driven at the falling edge of **SPC** and should be captured at the rising edge of **SPC**.

Both the read register and write register commands are completed in 16 clock pulses or in multiples of 8 in case of multiple bytes read/write. Bit duration is the time between two falling edges of **SPC**. The first bit (bit 0) starts at the first falling edge of **SPC** after the falling edge of **CS** while the last bit (bit 15, bit 23, ...) starts at the last falling edge of **SPC** just before the rising edge of **CS**.

bit 0: \overline{RW} bit. When 0, the data $DI(7:0)$ is written into the device. When 1, the data $DO(7:0)$ from the device is read. In the latter case, the chip drives **SDO** at the start of bit 8.

bit 1: \overline{MS} bit. When 0, the address remains unchanged in multiple read/write commands. When 1, the address is auto incremented in multiple read/write commands.

bit 2-7: address $AD(5:0)$. This is the address field of the indexed register.

bit 8-15: data $DI(7:0)$ (write mode). This is the data that is written into the device (MSb first).

bit 8-15: data $DO(7:0)$ (read mode). This is the data that is read from the device (MSb first).

In multiple read/write commands, further blocks of 8 clock periods are added. When the \overline{MS} bit is '0', the address used to read/write data remains the same for every block. When the \overline{MS} bit is '1', the address used to read/write data is increased at every block.

The function and the behavior of **SDI** and **SDO** remain unchanged.